

Infratec™ NOVA

The global standard for grain analysis.
Every grain counts.



Infratec™ NOVA gives you security, confidence and reliability in your grain analysis and is officially approved and established worldwide as the standard for determining protein, moisture, oil and starch.

Fair grain trading with the global standard in grain analysis

Infratec NOVA with the unique ANN calibration gives you results with outstanding accuracy and stability that enables you to analyse even the most unusual samples during difficult harvests. It is a global system for a global market built on 30 years of experience and harvest data comprising over 50,000 cross checked samples.

Keep the results flowing across the season

Stay in control of remote instruments through purpose built connectivity tools and monitor every instrument with remote diagnostics helping in rapid problem solving. Easy to plug and play instruments which enables instant swaps if needed during high season.

The most trusted way to ensure fair payment

The factory standardized instruments provide a common base for payment giving the exact same performance, reliability and repeatability. With the latest connectivity solutions offered by FOSS all instruments keep measuring the same regardless of local conditions making the Infratec™ NOVA the number one test for grain everyone agrees on.

Sample type

Wheat, barley, corn and other cereals, oilseeds, beans and pulses.

Parameters

Moisture, protein, oil, test weight, starch, wet gluten, fibre, ash and many more.

Technology

NIR Transmittance

Approvals

(as per EN 15948 standard)

Protected against dust and water splashes (IP54 certified)

Specifications

Feature	Specification
Dimensions (w x d x h)	410 x 460 x 445 mm
Weight	28.5 kg (31 kg with Test Weight Module)
Voltage	220-240V 50-60Hz or 110-120V
Rated current	1.0A (110-120V) / 0.5A (220-240V)
Fuse	T 5 A (250 V)
Power consumption	85 W (24 V)
Input supply	24 V DC from FOSS approved power supply
Spectrometer	Scanning monochromater
Wavelength range	400 - 1100 nm
Detector	Silicon
Optical bandwidth	7 nm
Number of data points/scan	1400
Mode	Transmittance
Light source	Tungsten halogen lamp
Detector	Silicon
Interface	Ethernet, 3 x USB (full function) including one on the instrument front for easy access
Display	10 inch capacitive touch screen
Noise level	< 70 dB(A)
Degree of protection	IP 54

Instrument management	
Networking software	FossManager™

Sample handling and result presentation	
Analysis time	Less than 60 seconds for 10 sub-samples including test weight analysis and as little as 40 seconds when dynamic sub-sampling enabled
Path length	Variable cell automatically controlled from 6 - 33 mm
Result report	Presented on the display as default. Can be sent to PC/LIMS and the printer port
Outlier function	Warnings and options for the presentation of the result
Software	Menu driven with touch screen interface
Regression programs	ANN (Artificial Neural Network); PLS (Partial Least Squares)
No. of sub-samples	Between 1 and 30 sub-samples (10 sub-samples standard)

PATENTED METHOD - US PATENTS; US 4,944,589 AND EUROPEAN PATENTS; EP 0 320 477 B1, 8704886-4.

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